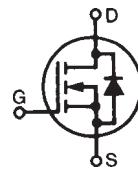


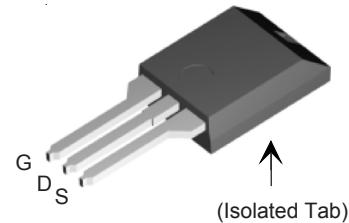
**PolarHV™ HiPerFET
Power MOSFET
ISOPLUS 220™
(Electrically Isolated Tab)**

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

V_{DSS} = 500 V
 I_{D25} = 15 A
 $R_{DS(on)}$ ≤ 260 mΩ
 t_{rr} ≤ 250 ns



ISOPLUS220™ (IXFC)
 E153432



G = Gate D = Drain
S = Source

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	500		V
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$; $R_{GS} = 1 M\Omega$	500		V
V_{GS}	Continuous	± 30		V
V_{GSM}	Transient	± 40		V
I_{D25}	$T_c = 25^\circ C$	15		A
I_{DM}	$T_c = 25^\circ C$, pulse width limited by T_{JM}	78		A
I_{AR}	$T_c = 25^\circ C$	26		A
E_{AR}	$T_c = 25^\circ C$	40		mJ
E_{AS}	$T_c = 25^\circ C$	1.0		J
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 A/\mu s$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 4 \Omega$	20		V/ns
P_D	$T_c = 25^\circ C$	130		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{stg}		-55 ... +150		°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300		°C
V_{ISOL}	50/60 Hz, RMS, $t = 1$, leads-to-tab	2500		V~
F_c	Mounting Force	11..65/2.5..15		N/lb
Weight		2		g

Symbol	Test Conditions ($T_J = 25^\circ C$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0 V$, $I_D = 250 \mu A$	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4 mA$	3.0		5.5 V
I_{GSS}	$V_{GS} = \pm 30 V_{DC}$, $V_{DS} = 0$		± 100	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	$T_J = 125^\circ C$	25	μA
			250	μA
$R_{DS(on)}$	$V_{GS} = 10 V$, $I_D = I_T$ Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2 \%$		260	mΩ

Features

- ▀ Silicon chip on Direct-Copper-Bond substrate
- ▀ High power dissipation
- ▀ Isolated mounting surface
- ▀ 2500V electrical isolation
- ▀ Low drain to tab capacitance(<30pF)

Applications

- ▀ DC-DC converters
- ▀ Battery chargers
- ▀ Switched-mode and resonant-mode power supplies
- ▀ DC choppers
- ▀ AC motor control

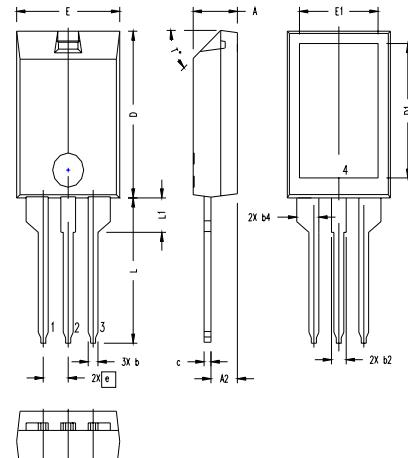
Advantages

- ▀ Easy assembly
- ▀ Space savings
- ▀ High power density

Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ C$, unless otherwise specified)	Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10 V; I_D = I_T$, pulse test	18	28	S	
C_{iss}		3600		pF	
C_{oss}		380		pF	
C_{rss}		48		pF	
$t_{d(on)}$		20		ns	
t_r		25		ns	
$t_{d(off)}$	$V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = I_T$	58		ns	
t_f	$R_G = 4 \Omega$ (External)	20		ns	
$Q_{g(on)}$		65		nC	
Q_{gs}		20		nC	
Q_{gd}		20		nC	
R_{thJC}			0.21	0.95 $^\circ C/W$	
R_{thCS}					$^\circ C/W$

Source-Drain Diode**Characteristic Values**
($T_J = 25^\circ C$, unless otherwise specified)

Symbol	Test Conditions	Min.	Typ.	Max.
I_s	$V_{GS} = 0 V$			26 A
I_{SM}	Repetitive			78 A
V_{SD}	$I_F = I_S, V_{GS} = 0 V$, Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$			1.5 V
t_{rr}	$I_F = 25 A$ $-di/dt = 100 A/\mu s$		250 ns	
Q_{RM}	$V_R = 100 V, V_{GS} = 0 V$	0.3		μC

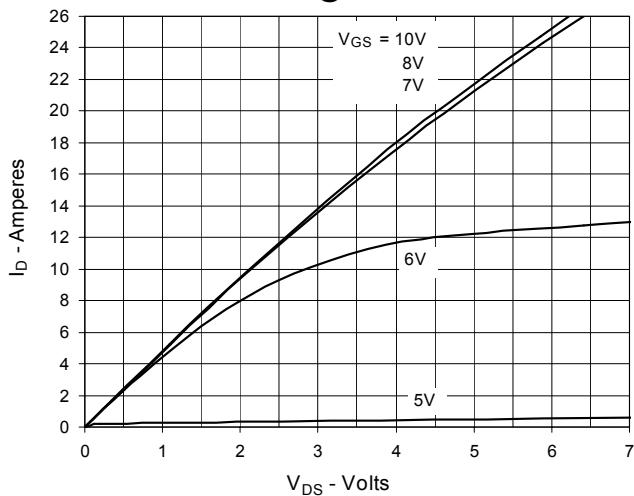
Note: Test Current $I_T = 13A$ **ISOPLUS220 Outline**

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.157	.197	4.00	5.00
A2	.098	.118	2.50	3.00
b	.035	.051	0.90	1.30
b2	.049	.065	1.25	1.65
b4	.093	.100	2.35	2.55
c	.028	.039	0.70	1.00
D	.591	.630	15.00	16.00
D1	.472	.512	12.00	13.00
E	.394	.433	10.00	11.00
E1	.295	.335	7.50	8.50
e	.100	BASIC	2.55	BASIC
L	.512	.571	13.00	14.50
L1	.118	.138	3.00	3.50
T*			42.5°	47.5°

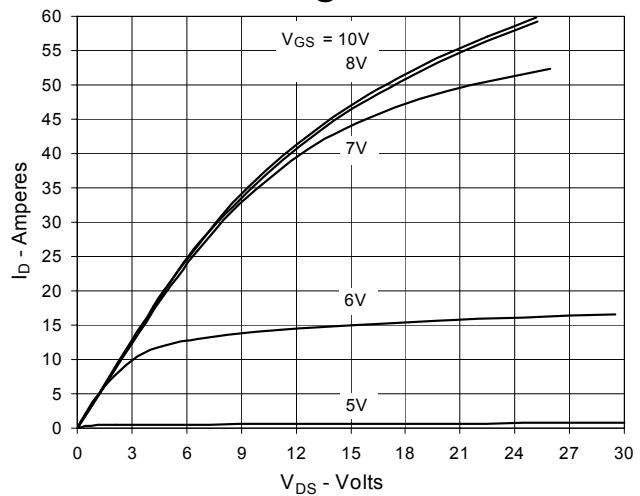
NOTE:

- Bottom heatsink (Pin 4) is electrically isolated from Pin 1, 2, or 3.
- This drawing will meet dimensional requirement of JEDEC SS Product Outline TO-273 except D and D1 dimension.

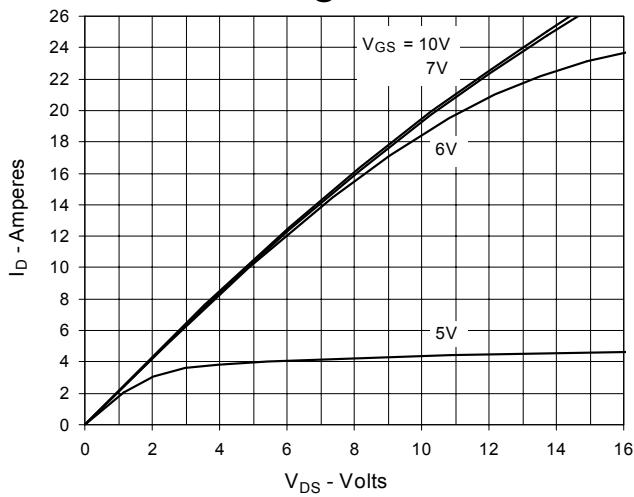
**Fig. 1. Output Characteristics
@ 25°C**



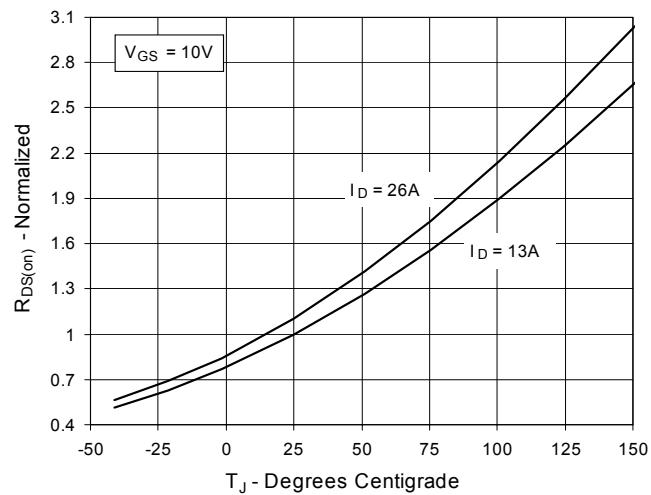
**Fig. 2. Extended Output Characteristics
@ 25°C**



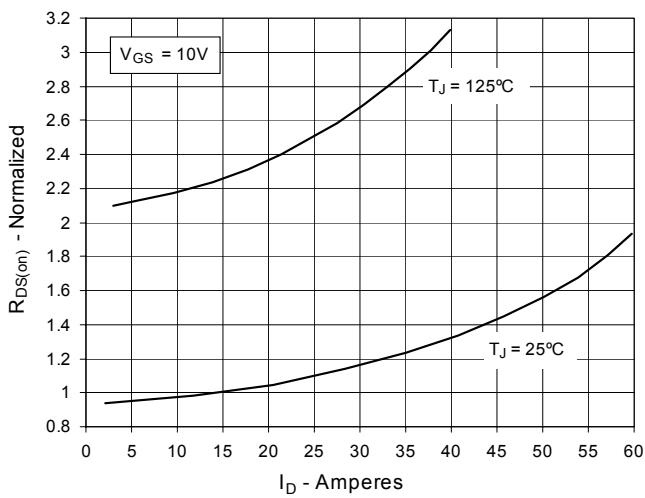
**Fig. 3. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 13A$ Value
vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 13A$ Value
vs. Drain Current**



**Fig. 6. Maximum Drain Current vs.
Case Temperature**

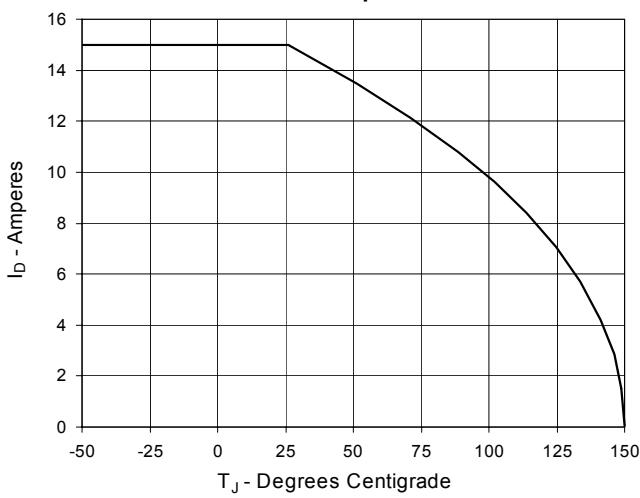


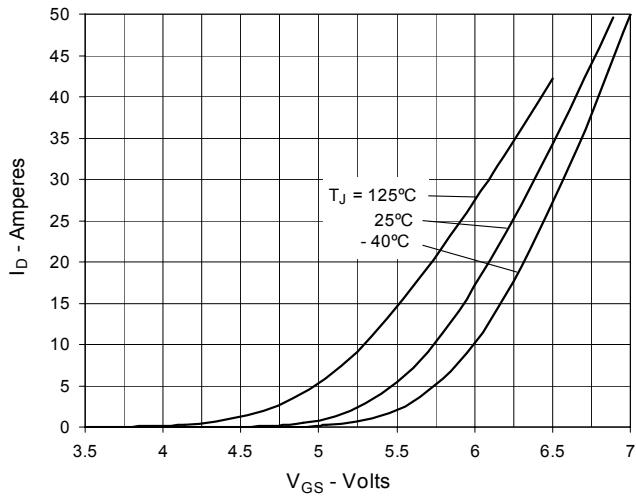
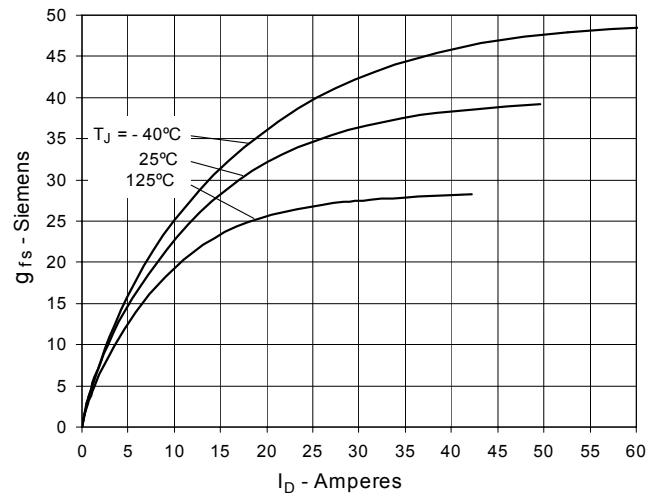
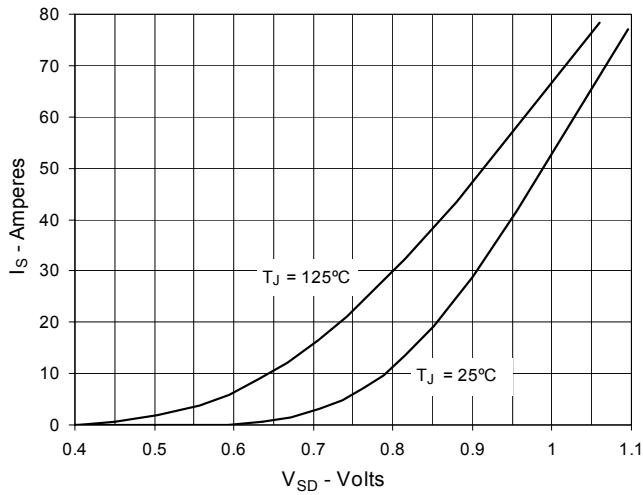
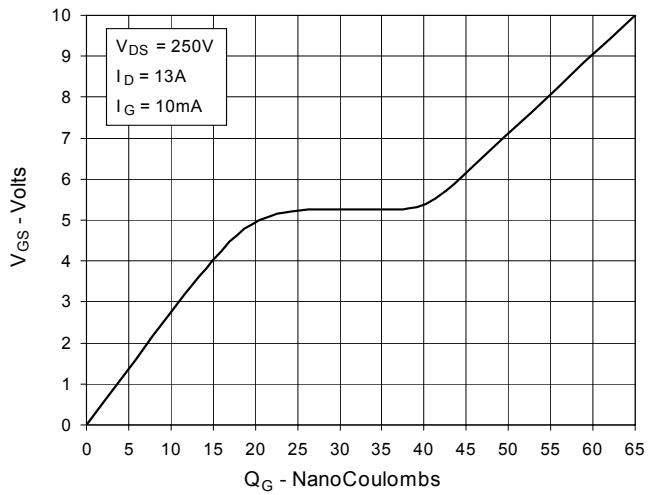
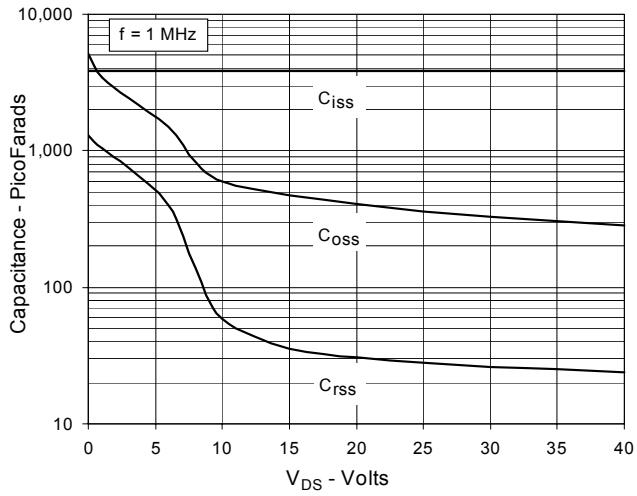
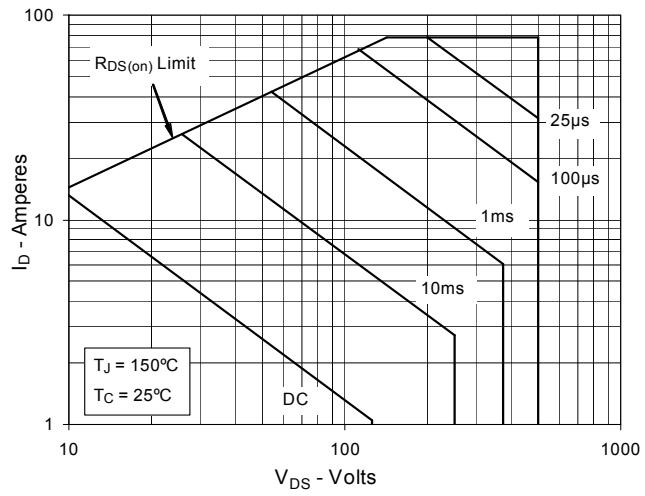
Fig. 7. Input Admittance**Fig. 8. Transconductance****Fig. 9. Forward Voltage Drop of Intrinsic Diode****Fig. 10. Gate Charge****Fig. 11. Capacitance****Fig. 12. Forward-Bias Safe Operating Area**

Fig. 13. Maximum Transient Thermal Resistance